

GEMs at the FTD

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FTD Electronics & Applications Seminar
19th May 2025

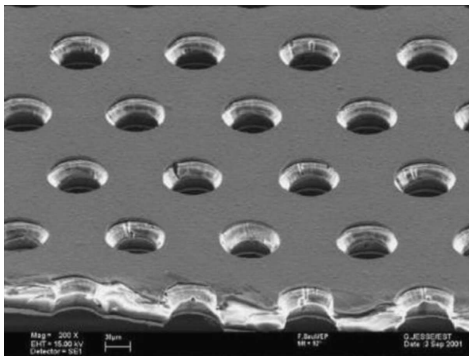


- 1 Overview GEMs
- 2 Detailed production steps
- 3 Quality assurance
- 4 Latest results



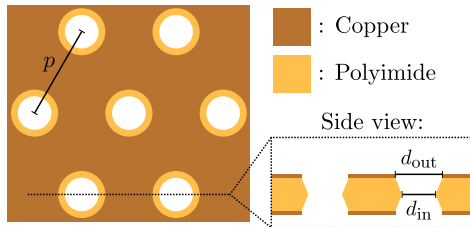
[pictures by V. Lannert]

1. Overview on GEMs



[F. Sauli, *The gas electron multiplier (GEM): Operating principles and applications*, 2016]

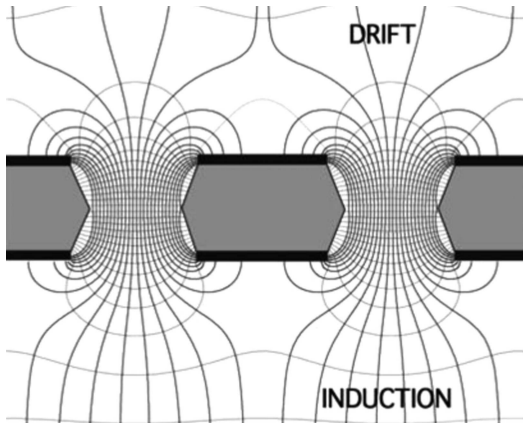
- **Gas Electron Multiplier** (GEM)
- Variant of the **Micro Pattern Gaseous Detectors** (MPGDs)
- Developed by Fabio Sauli in 1996
- 50 μm polyimide, coated with 5 μm copper
- Polyimide has interesting properties:
 - Dielectric strength $\geq 200 \frac{\text{V}}{\mu\text{m}}$
 - specific resistivity $= 8 \cdot 10^{15} \Omega \text{ m}$
- Manufactured using [photolithography](#)



[P. Hauer, PhD thesis, 2022]

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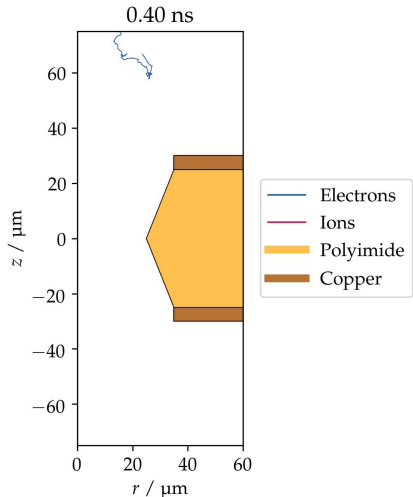
WORKING PRINCIPLE OF GEMs



[F. Sauli, *The gas electron multiplier (GEM): Operating principles and applications*, 2016]

- Microscopic holes are etched into the foil (50 μm to 70 μm)
- Applying voltage \Rightarrow Gas amplification happens within holes due to strong \vec{E} -field
- Gain depends exponentially on voltage, but ranges from 5 - 20
- Holes typically arranged hexagonally, pitch $p = 140 \mu\text{m}$ (standard pitch)
 $\Rightarrow \approx 60$ holes per mm^2 , making the foil partially transparent

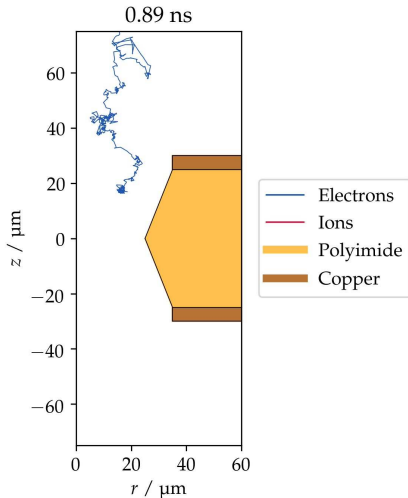
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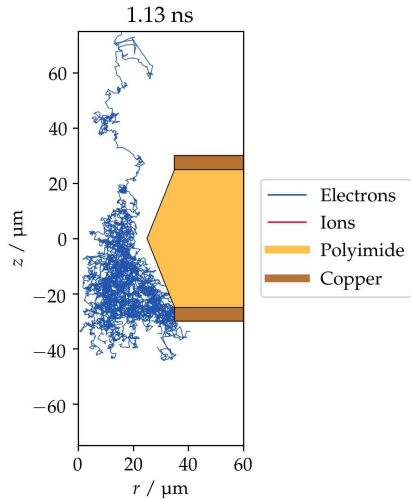
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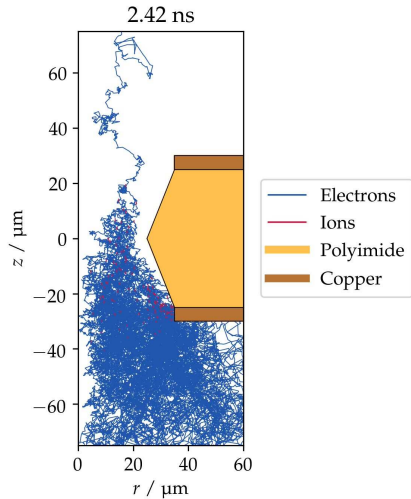
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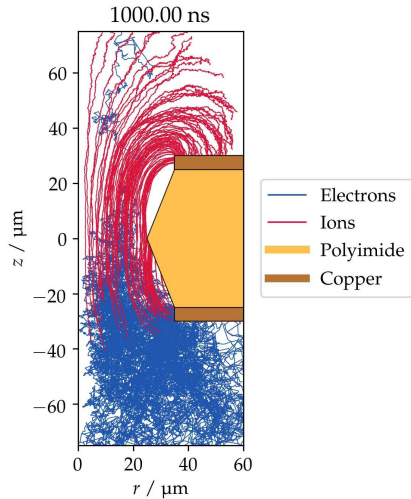
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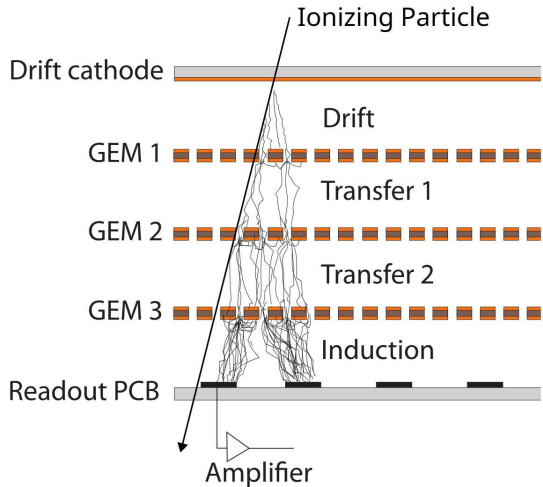
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EXAMPLES OF GEM DETECTORS

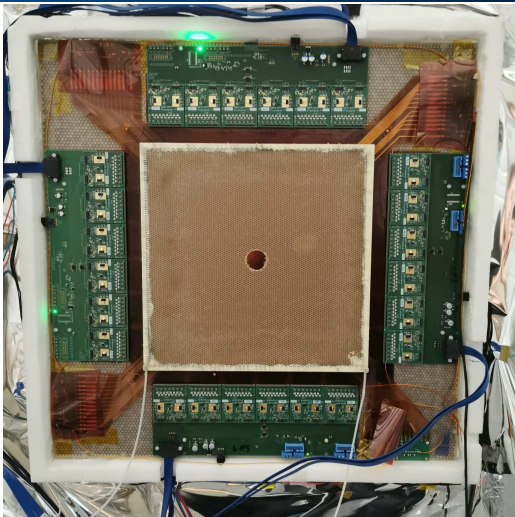


Prominent examples:

- ▶ Triple GEM tracking detectors (e.g. AMBER / COMPASS / INSIGHT)
- ▶ GEM time projection chamber (TPC) (e.g. ALICE / FOPI / etc.)

[Colaleo et al., *CMS TDR for the Muon Endcap GEM Upgrade*, 2015], modified

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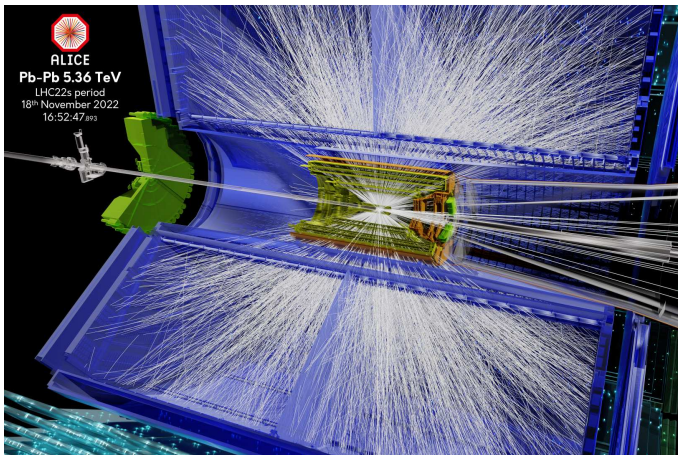


[AG Ketzer, 2022]

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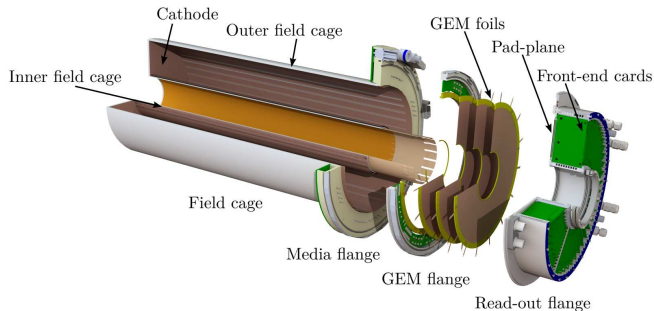


[<https://cds.cern.ch/record/2841865>]

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EXAMPLES OF GEM DETECTORS



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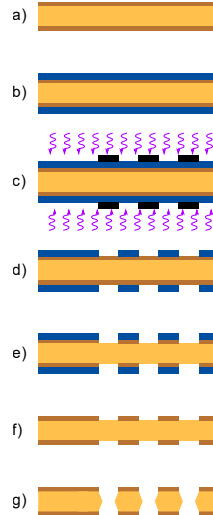
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[Berger et al., *A Large Ungated TPC with GEM Amplification*, 2017]

GEM PRODUCTION STEPS

Seven steps to produce a GEM:

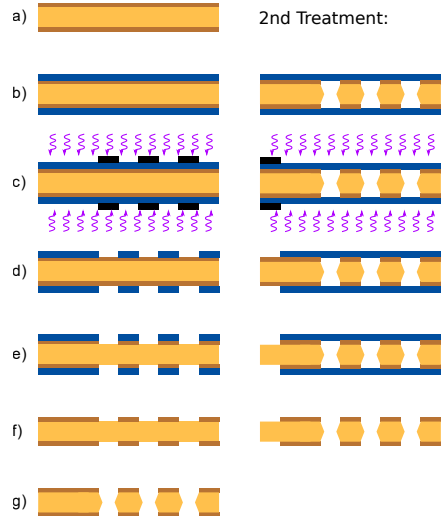
- 1 Lamination with photoresist (b)
- 2 Exposition with UV light (c)
- 3 Photoresist development (d)
- 4 Copper etching (e)
- 5 Stripping of photoresist (f)
- 6 Chromium etching (f)
- 7 Polyimide etching (g)



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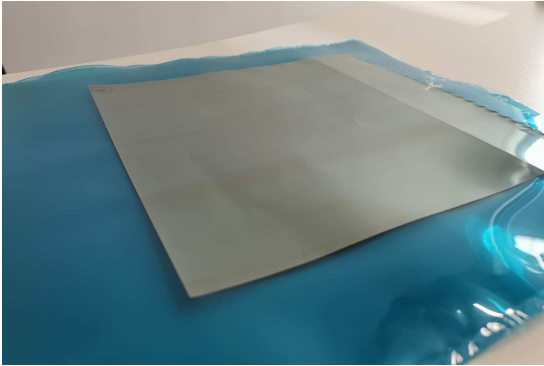


2. Detailed production steps

STEP 1-3: PATTERNING OF PHOTORESIST

Lamination

- Use negative dry film photoresist (15 μm)
- Laminating both sides simultaneously



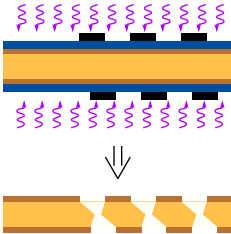
RLM419p by Bungard



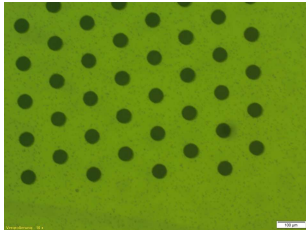
STEP 1-3: PATTERNING OF PHOTORESIST

Exposition

- Using UV LEDs from both sides
- Crucial step: alignment of top and bottom mask
 - ⇒ Align masks once under microscope and glue them together (pocket)



Aligned masks:

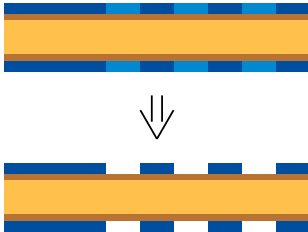


Exp 3040 LED by
Bungard

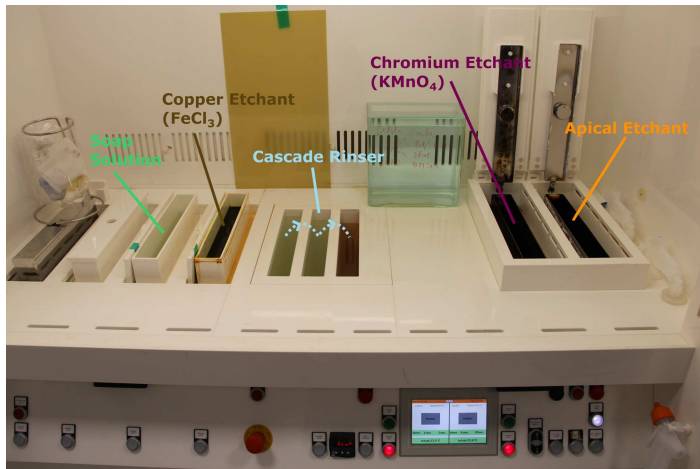
STEP 1-3: PATTERNING OF PHOTORESIST

Development

- Dissolve photoresist which has not been exposed
- Performed in beaker with Na_2CO_3 -based solution



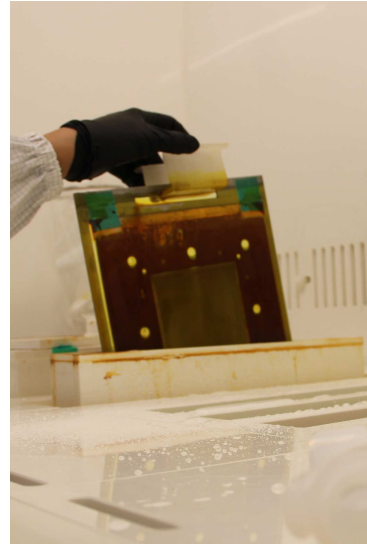
- Installed in ISO 7 of cleanroom
- Especially designed/built for GEM production
 - 3 stainless steel beaker
 - 3 PP beaker (non-heated)
 - cascade rinser
 - generously designed exhaust



STEP 4: COPPER ETCHING



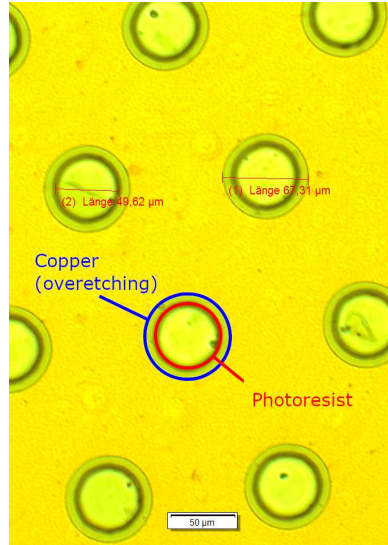
- Etch accessible copper through patterned photoresist
- Performed in beaker with FeCl_3 -based solution
- Etches isotropically:
 - Copper below photoresist is partially etched away, creating larger diameter



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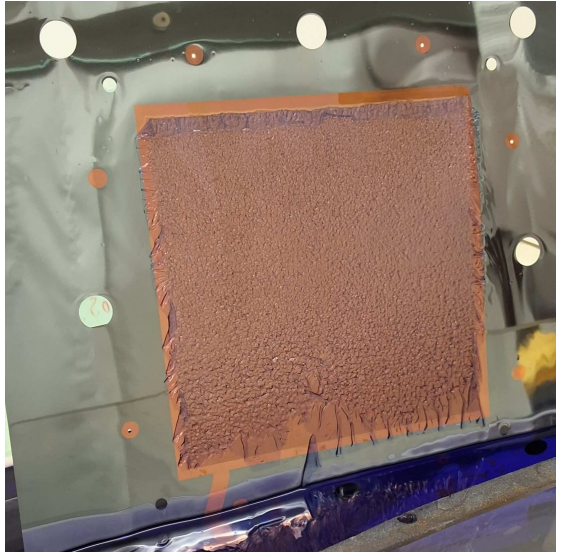
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STEP 5: STRIPPING OF PHOTORESIST

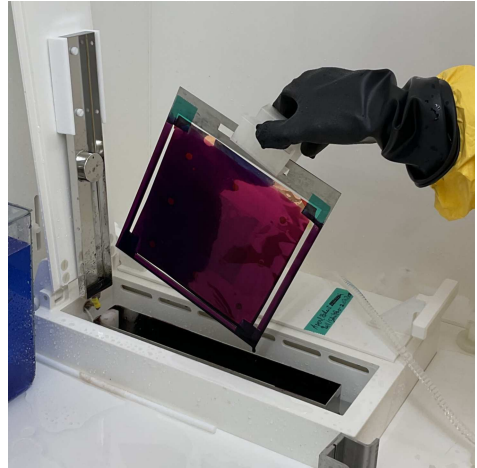
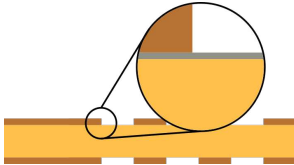


- Mixture of Aceton and Ethanol
 - Photoresist peels off
 - Does not dissolve photoresist
- Sometimes help with small brush to get rid of photoresist



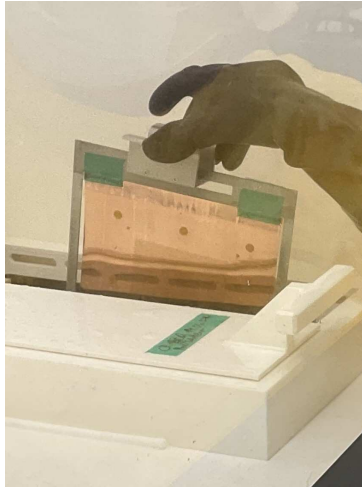
STEP 6: CHROMIUM ETCHING

- Adhesive layer between copper and polyimide
 - Typically only a few nm thick
- Etching performed in beaker with KMnO_4 -based solution
- Then neutralize with aqueous solution

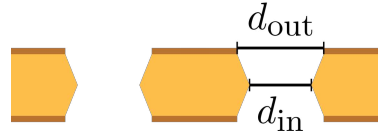


STEP 7: POLYIMIDE ETCHING

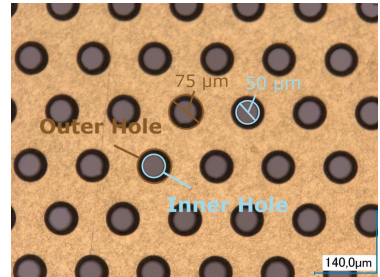
- Strong and really dangerous chemicals involved
- Heated up
- Afterwards: Outer and inner holes visible under microscope
 - Outer diameter: $d_{\text{out}} \approx 75 \mu\text{m}$
 - Inner diameter: $d_{\text{in}} \approx 50 \mu\text{m}$



Cross Section:

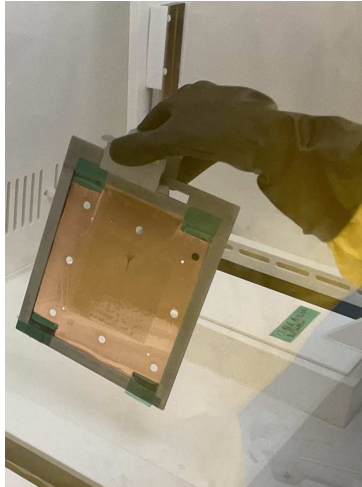


[P. Hauer, PhD thesis, 2022], edited

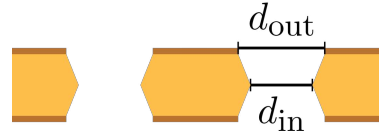


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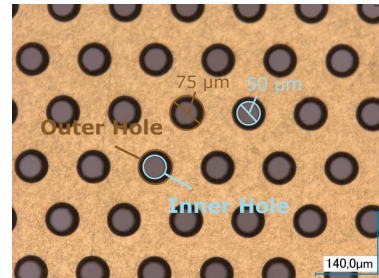
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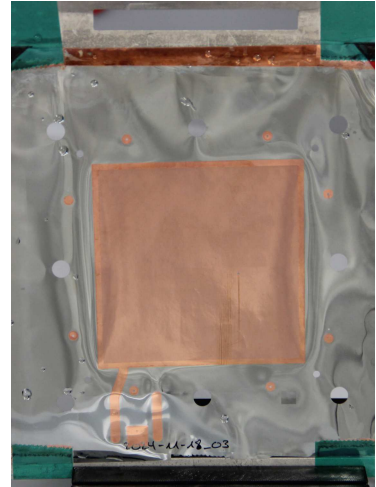
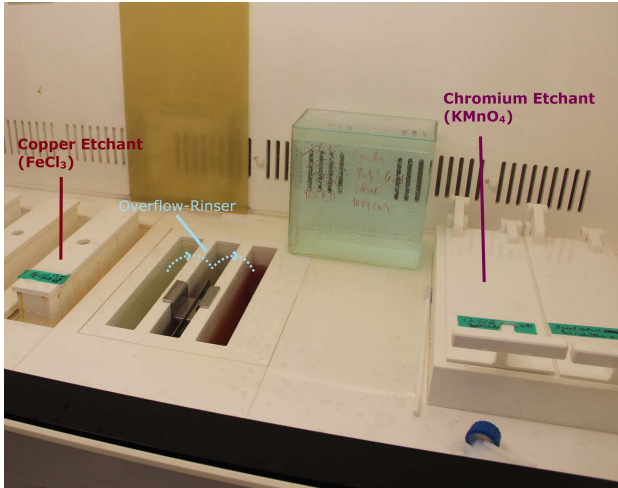


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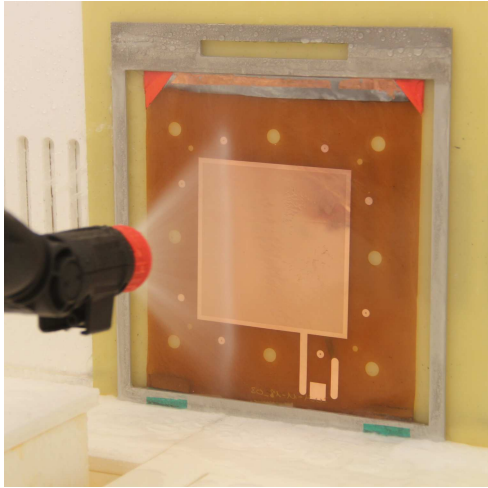
STEP 8: 2ND TREATMENT & CLEANING

Repeat steps 1 to 6 for electrode patterning and clean using high-pressure DI water



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3. Quality assurance

QUALITY ASSURANCE OF GEMs

High quality of GEMs is key for **optimal** and **longterm** detector performance

⇒ Quality Assurance (QA) is very important

➤ The previous process (e.g. ALICE, CMS, COMPASS) includes:

➤ Optical QA:

- number and size of defects (visual inspection by eye and microscope)
- size/uniformity of inner and outer holes

➤ Electrical QA:

- leakage current measurements
- high-voltage stability

⇒ **spatially resolved detection of electric discharges is desired**

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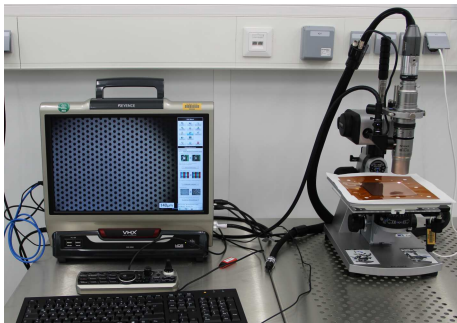
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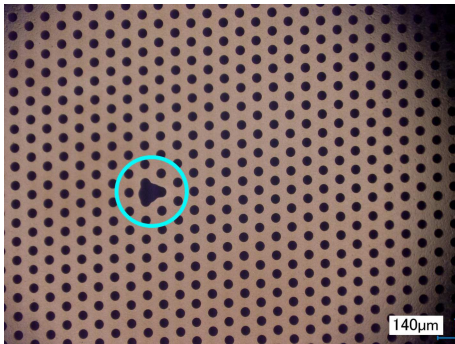
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Digital microscope Keyence VHX 2000

QUALITY ASSURANCE OF GEMs



Microscope picture of a defect
(connected holes)

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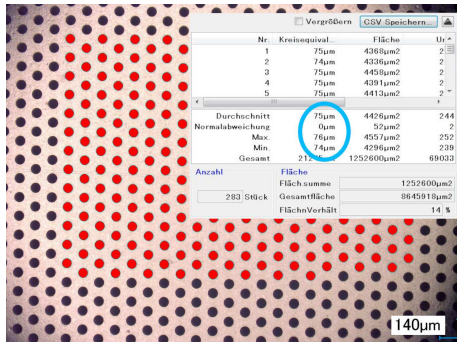
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Microscope picture with measurement of outer hole diameter (copper)

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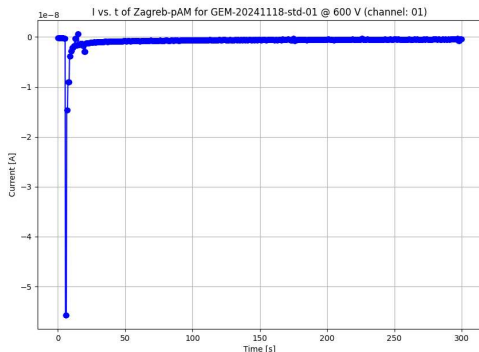
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Measurement of leakage current
 $\approx 0.4 \text{ nA @ } 600 \text{ V}$

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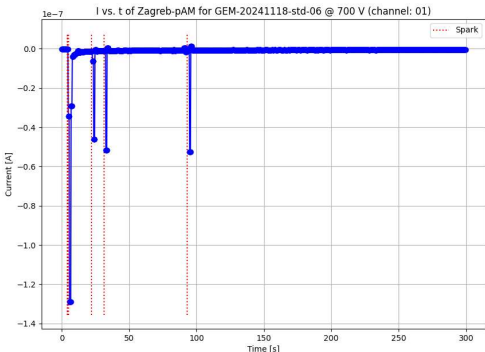
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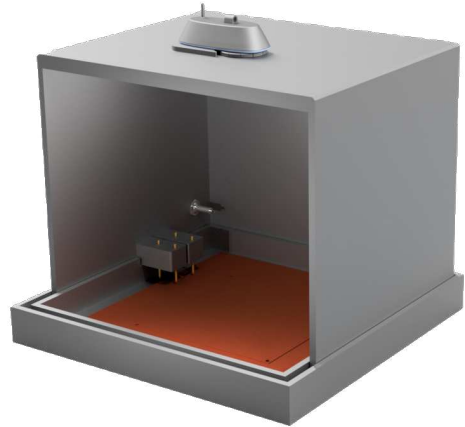
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Measurement of leakage current
 ≈ 0.5 nA (with 8 sparks) @ 700 V

DESIGN OF THE SMALL SDS

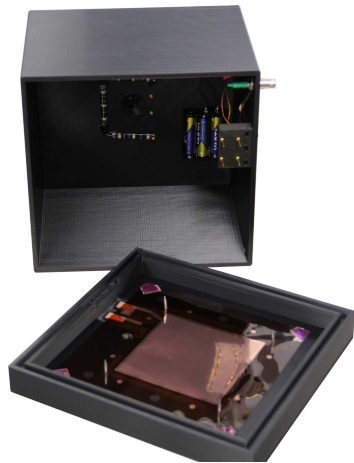
- Requirements for smaller design:
 - sufficiently large for uncut $10 \times 10 \text{ cm}^2$ GEMs ($\Rightarrow \approx 20 \times 20 \text{ cm}^2$)
 - easy & cost-effective to manufacture (3d printed)
 - simple, non-invasive HV connection
 - clean room suitable
 - low leakage current ($I_{\text{leak}} < 25 \text{ pA}$)
 - camera mount in the middle above the GEM



rendered image of the SDS design
(section view)

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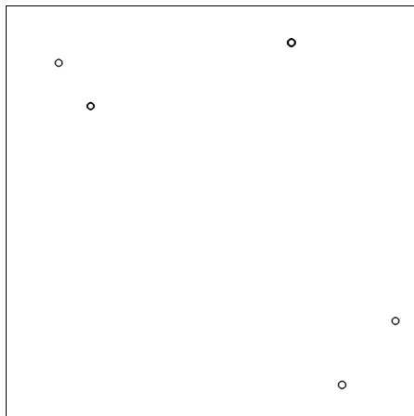


finished Spark Detection System (SDS) with a GEM-foil inside

EXAMPLE SDS MEASUREMENTS

- Software makes use of python and library OpenCV for ease of use
- Primarily threshold scan, then SimpleBlobDetector()
- Save time, position and brightness of spark in text file
- Draw spark on sparkmap
- Test shows: efficiency
 $\epsilon \geq (95.5 \pm 0.7) \%$

20241118-std-06 at 700 V for 300 s



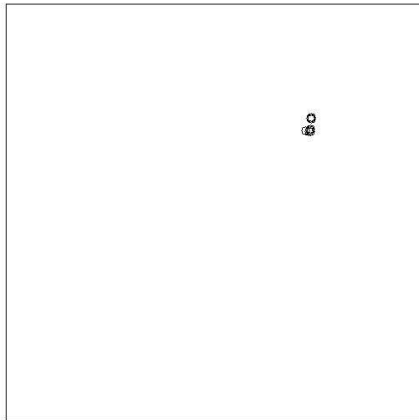
Sparkmap of typical GEM

EXAMPLE SDS MEASUREMENTS

20230613—STD—01 at 600 V for 300 s

CON

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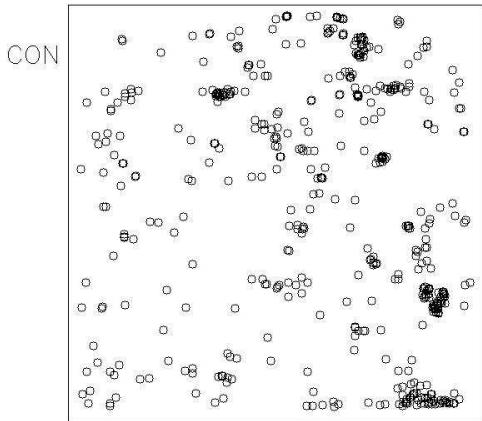


Sparkmap of GEM with crinkle → bad

EXAMPLE SDS MEASUREMENTS

GEM 2023-08-28-02 at 600 V for 600s

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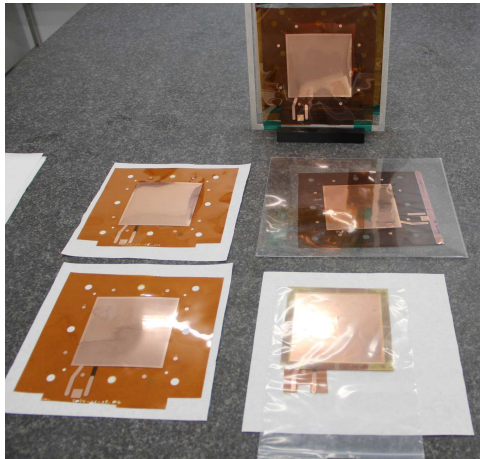


Sparkmap of very bad GEM

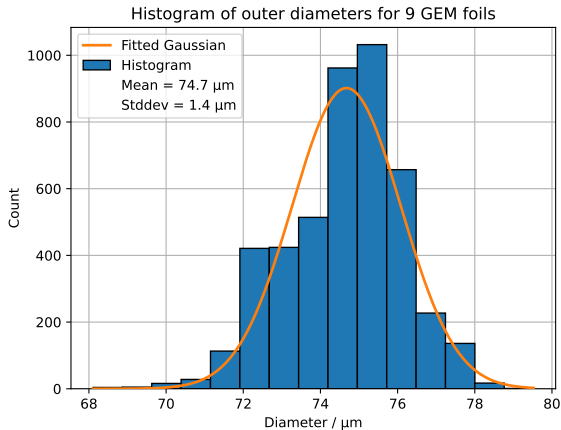
4. Present results

PRODUCED FOILS

- Took some time to produce high-quality foils reliably
- Electrical QA requirements (from previous experiences):
 - $I_{\text{leak}} \leq 2 \text{ nA}$
(stored in dry-cabinet)
 - little to no discharges even @ $\geq 500 \text{ V}$
- Most foils directly fulfill this condition ($\approx \frac{9}{10}$)
- Remaining ones can be retreated until they meet requirements



HOLE STATISTICS

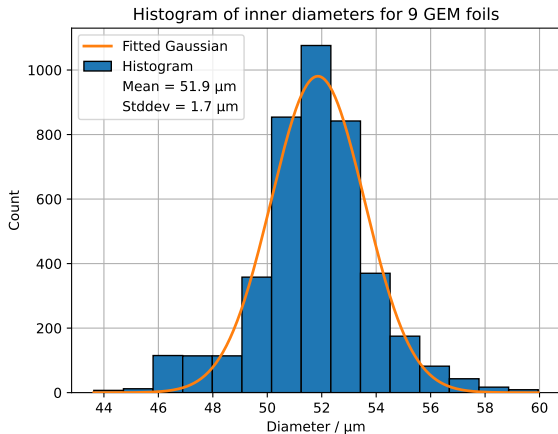


(Preliminary)

Measured hole diameters across 9 recently produced foils

- Outer:
- Across different foils:
 $(74.7 \pm 1.4) \mu\text{m}$
- Within one foil (exemplary):
 $(73.8 \pm 1.3) \mu\text{m}$
- Inner:
- Across different foils:
 $(51.9 \pm 1.7) \mu\text{m}$
- Within one foil (exemplary):
 $(51.4 \pm 1.4) \mu\text{m}$

HOLE STATISTICS



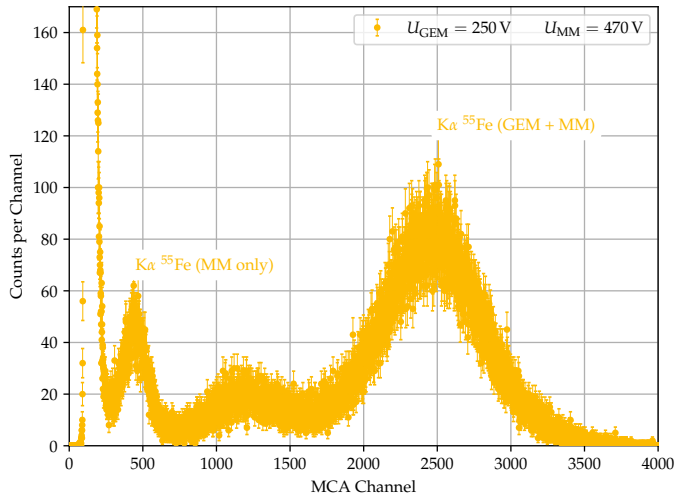
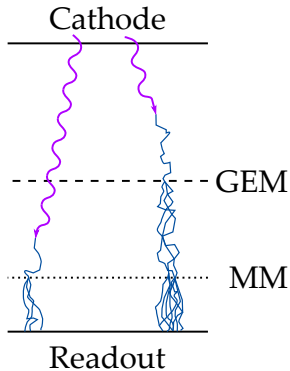
(Preliminary)

Measured hole diameters across 9 recently produced foils

- Outer:
- Across different foils:
 $(74.7 \pm 1.4) \mu\text{m}$
- Within one foil (exemplary):
 $(73.8 \pm 1.3) \mu\text{m}$
- Inner:
- Across different foils:
 $(51.9 \pm 1.7) \mu\text{m}$
- Within one foil (exemplary):
 $(51.4 \pm 1.4) \mu\text{m}$

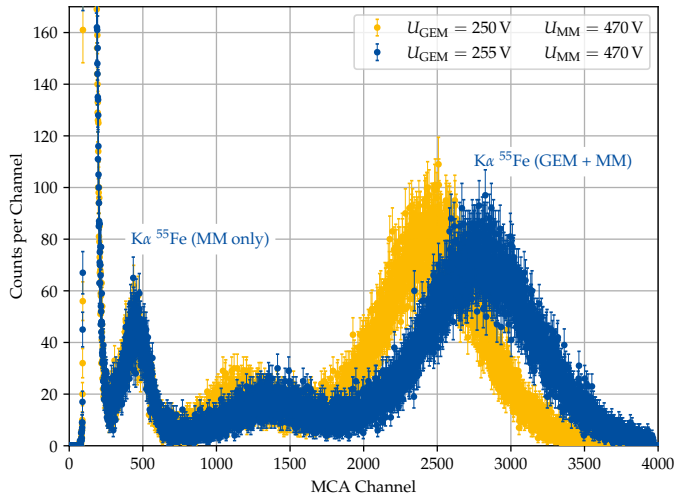
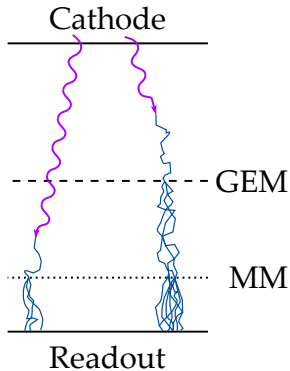
FIRST FE55 SPECTRA

Performed a test measurement with a hybrid detector (MM + GEM)



FIRST FE55 SPECTRA

Performed a test measurement with a hybrid detector (MM + GEM)



Summary

- Successful implementation of a process to produce $10 \times 10 \text{ cm}^2$ GEM foils for research and development purposes (other possible use cases, e.g. flex PCs)
- Investigated the achievable quality of the foils using optical and electrical QA
- Most produced foils are (very) good if none are lost due to handling issues

Outlook

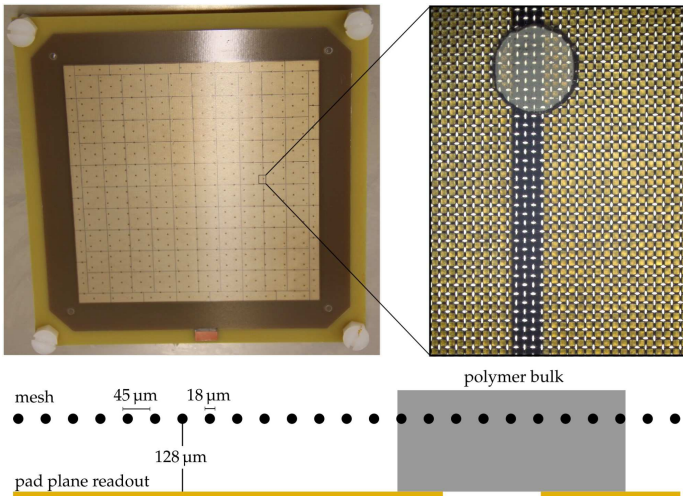
- Look into improvements to make the process more efficient or reliable
- Try different pitches, hole sizes and geometries (e.g. using MLA) to investigate important characteristics (IBF, energy resolution, gain)

Thanks for your attention!

Tim Schüttler - schuettler@hiskp.uni-bonn.de

Markus Ball, Yevgen Bilevych, Philip Hauer, Shania Müller, Dmitri Schaab,
Bernhard Ketzer

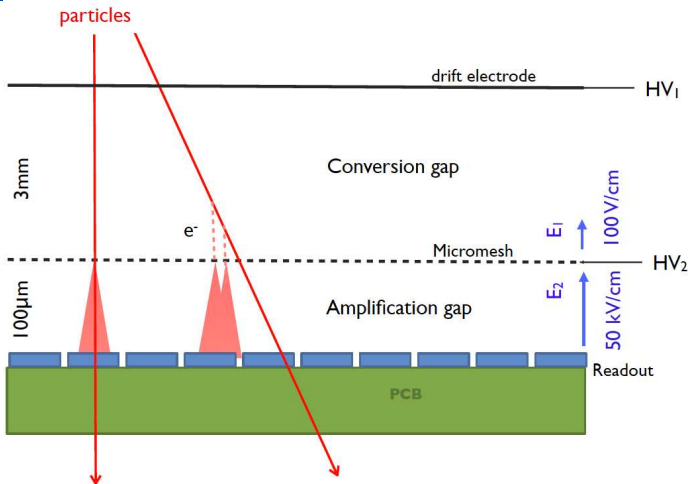
Backup



- **Micro-Mesh Gaseous Structure**
- Another variant of MPGDs
- Invented in 1996

[P. Hauer, PhD thesis, 2022]

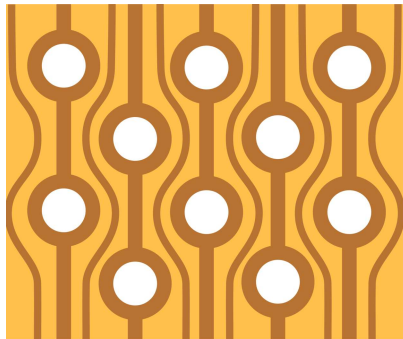
MICROMEAS



- **Micro-Mesh Gaseous Structure**
- Another variant of MPGDs
- Invented in 1996

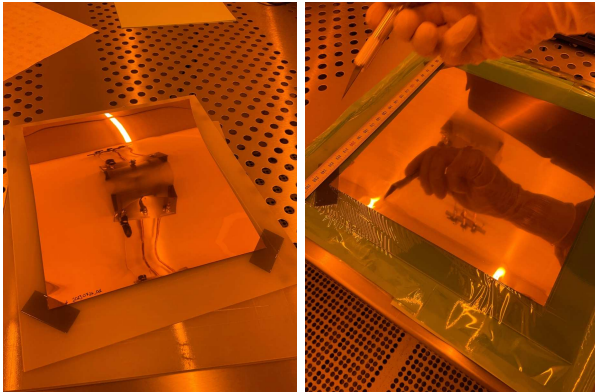
[Jeanneau et al., *Performances and ageing study of resistive-anodes Micromegas detectors for HL-LHC environment*, 2012], edited

- Additional amplification stage at the bottom side of the GEM
- Highly reduced IBF ($< 1\%$)
- 2nd treatment with perfectly aligned mask
- So far only small samples ($\approx 2\text{ cm} \times 2\text{ cm}$)
- Production of larger samples could be possible with MLA



STEP 1: LAMINATION

- Use negative dry film photoresist (15 μm)
- Up to now: lamination of each side individually



RLM419p by Bungard

STEP 4: COPPER ETCHING - SPRINT

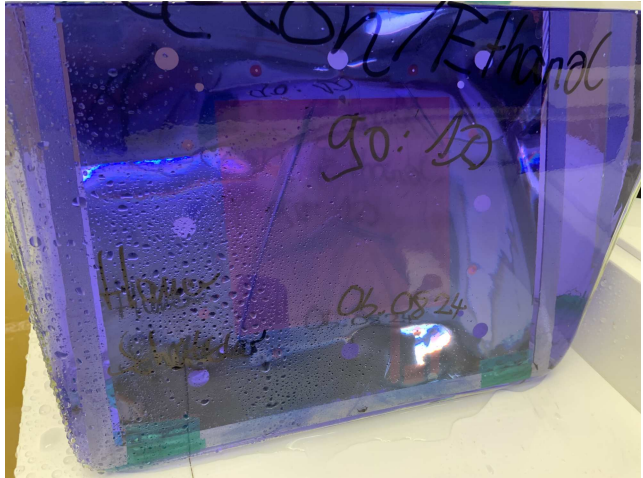
- Etch accessible copper through holes in photoresist
- Performed in beaker with FeCl_3 -based solution
- Expected overetching
 - Copper below photoresist is partially etched away
- Investigated different approaches
 - Spraying of chemical did not work properly (Sprint machine)



Sprint 3000 by Bungard

STEP 5: STRIPPING OF PHOTORESIST

- Mixture of Aceton and Ethanol
 - Photoresist peels off
 - Does not dissolve photoresist
- Sometimes help with small brush to get rid of photoresist

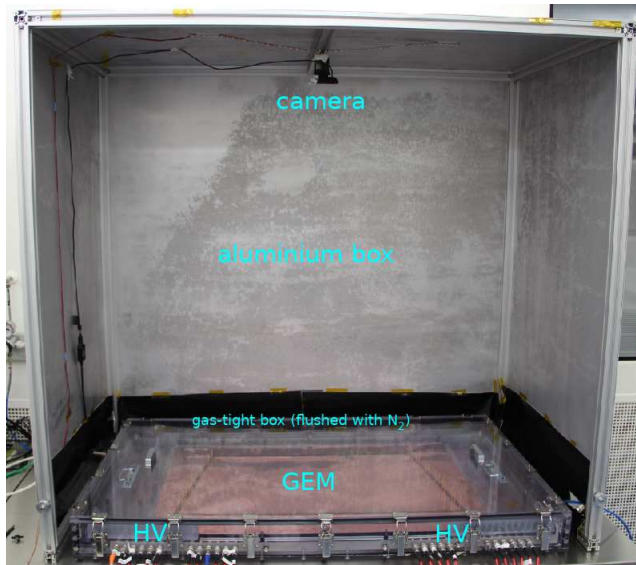


LARGE SDS USED FOR ALICE GEM QA

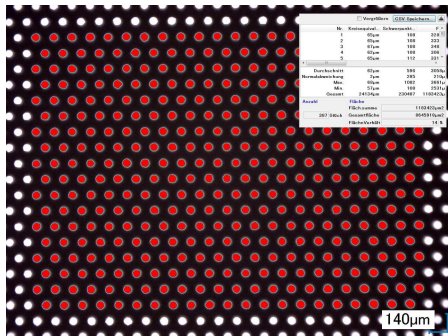
- Working principle and crucial features:
 - camera observes electric discharges
 - aluminum box needs to be dark/lightproof
 - shielding for leakage current measurement

see:

DOI 10.1088/1742-6596/1498/1/012056



QUALITY ASSURANCE OF GEMs



Microscope picture with measurement of inner holes (polyimide)

* see: DOI 10.1088/1748-0221/12/01/C01081

High quality of GEMs is key for **optimal** and **longterm** detector performance.

⇒ Quality Assurance (QA) is very important

➤ The previous process (e.g. ALICE*, CMS, COMPASS) includes:

➤ Optical QA:

- number and size of defects (visual inspection by eye and microscope)
- size/uniformity of inner and outer holes

➤ Electrical QA:

- leakage current measurements
- high-voltage stability

⇒ **spatially resolved detection of electric discharges is desired**

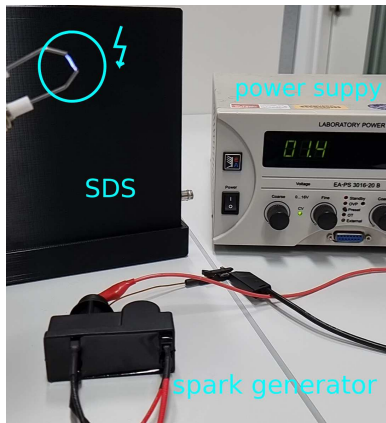


- Used camera:
Logitech HD C270:
 - 0.9 MP (1280 × 720 pixel)
 - up to 30 FPS
 - USB-A 2.0
 - easily attachable
 - affordable (≤ 20 €)

source: <https://www.logitech.com/de-de/products/webcams/c270-hd-webcam.960-001063.html>

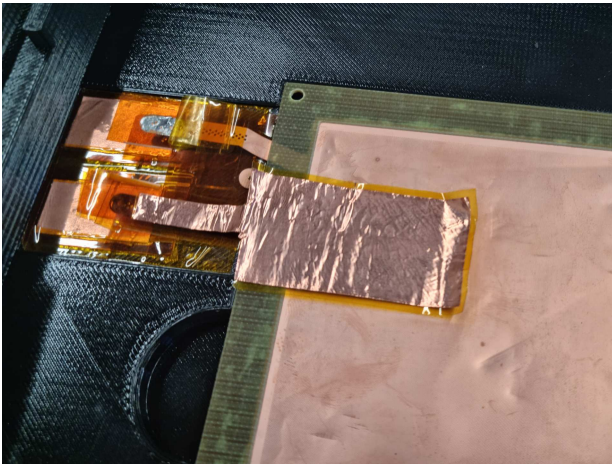
EFFICIENCY TESTING SETUP

- Use spark generator to create short, stable periodic HV pulses
- Imitate a sparking GEM by creating sparks on top of it
- Count missed sparks by calculating the time difference between detected sparks and find outliers
- Calculate efficiency at different spark rates (vary spark frequency with power supply)



⇒ Test the efficiency of the system in different exceptional cases

EFFICIENCY TESTING SETUP - ADDENDUM

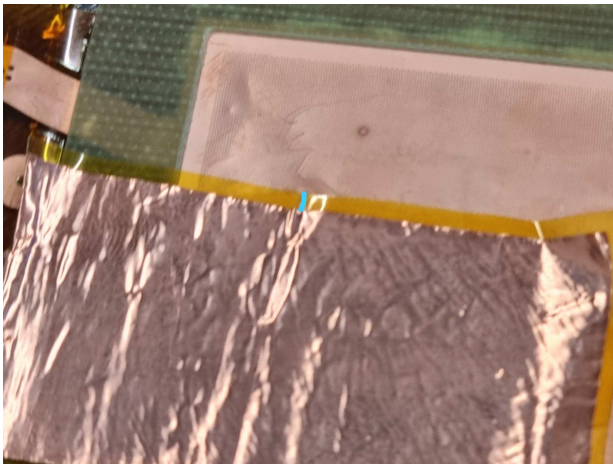


➤ How to get sparks on top of the GEM:

- piece of copper tape
- insulate with polyimide
- apply HV between copper tape and topside of the GEM

⇒ Comparable to real spark inside GEM hole

EFFICIENCY TESTING SETUP - ADDENDUM



➤ How to get sparks on top of the GEM:

- piece of copper tape
- insulate with polyimide
- apply HV between copper tape and topside of the GEM

⇒ Comparable to real spark inside GEM hole

spark frequency	efficiency ε
10.49 Hz	$(96.6 \pm 0.5) \%$
6.33 Hz	$(95.5 \pm 0.7) \%$
3.36 Hz	$(97.2^{+0.7}_{-0.8}) \%$

- Note: different errors for \pm due to error propagation
 - based on: "Review of Particle Physics", PDG, Zyla, P. A. and others, 2020

- Satisfying efficiency, even for high spark rates
 - 10.5 Hz \Rightarrow typically only 2 empty frames between sparks
 - close to limit of the current system
- Efficiency certainly high enough for regular use cases